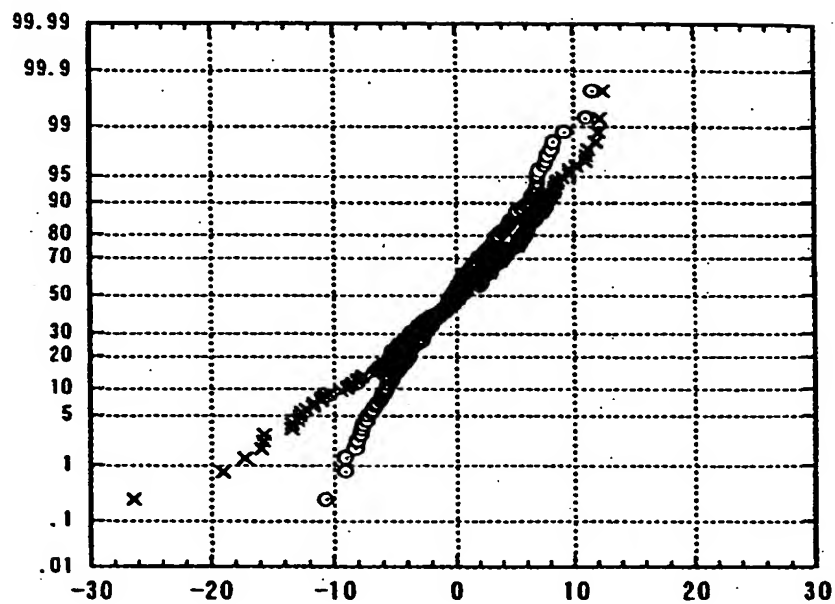




FIG.1

○ present invention
× conventional technique



ON current value fluctuation in adjacent TFTs[%]

FIG.2A

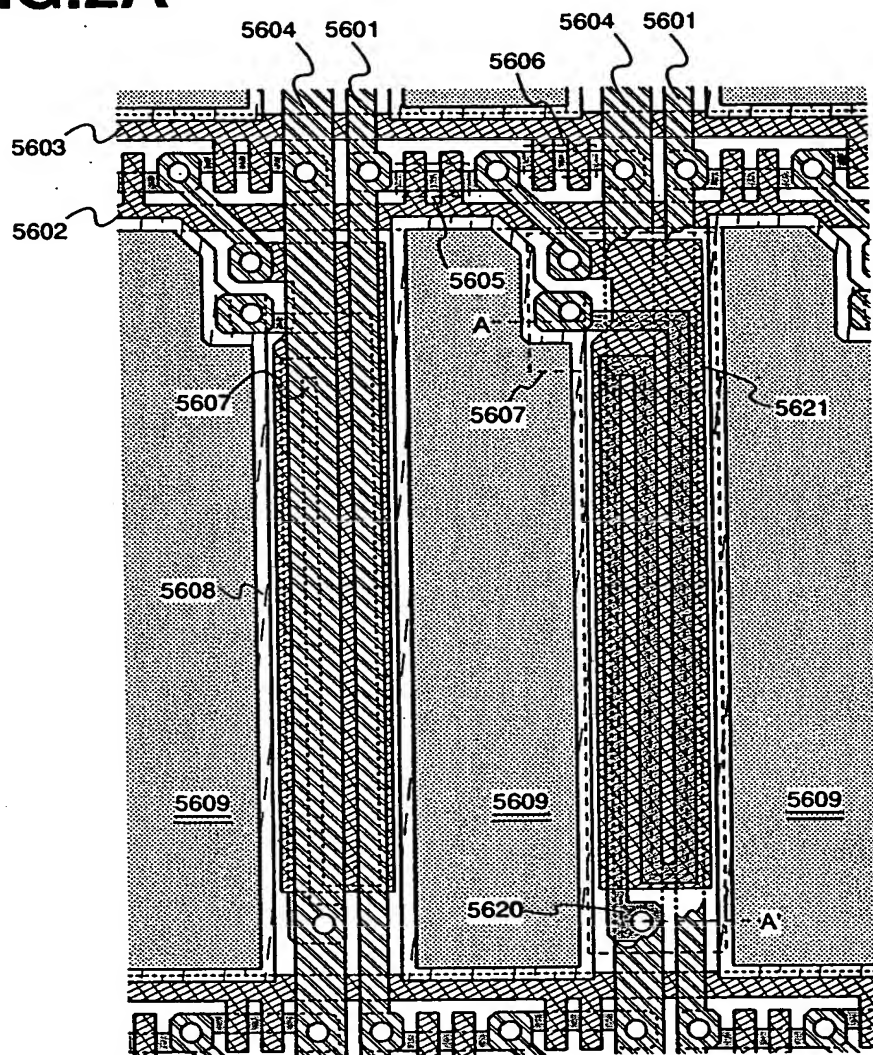


FIG.2B

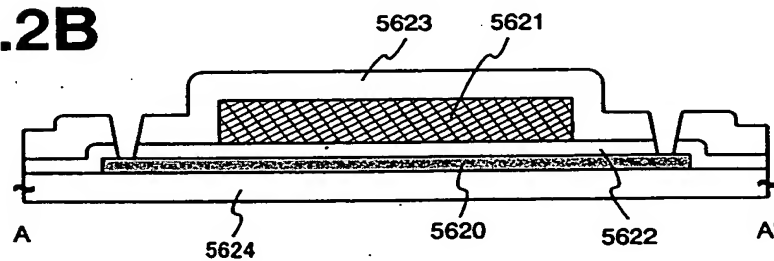


FIG.3A

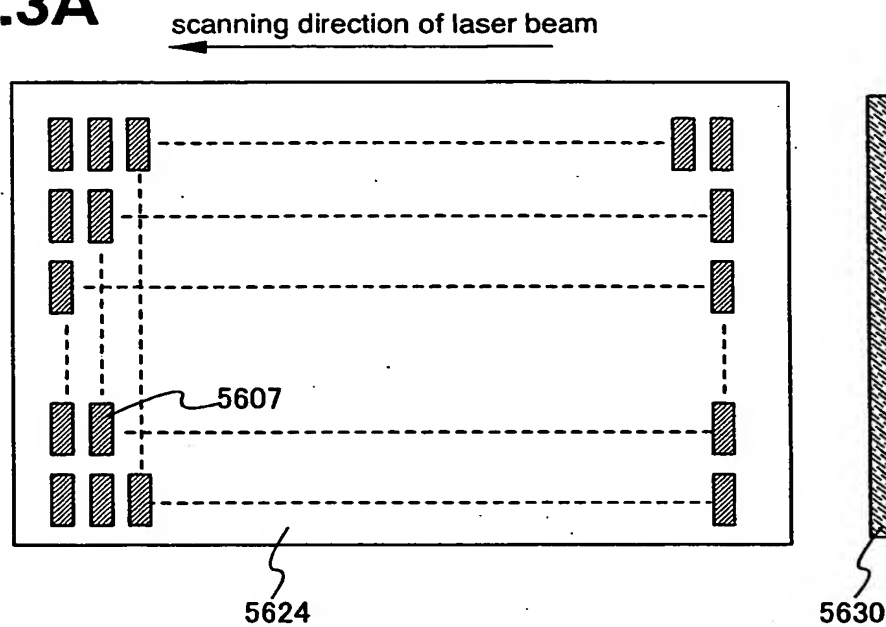


FIG.3B

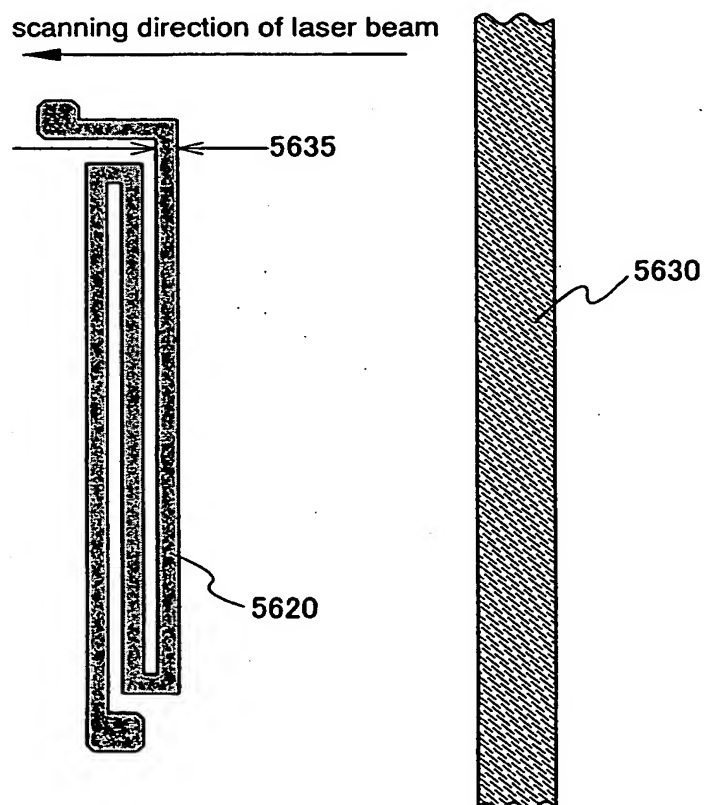


FIG.4A

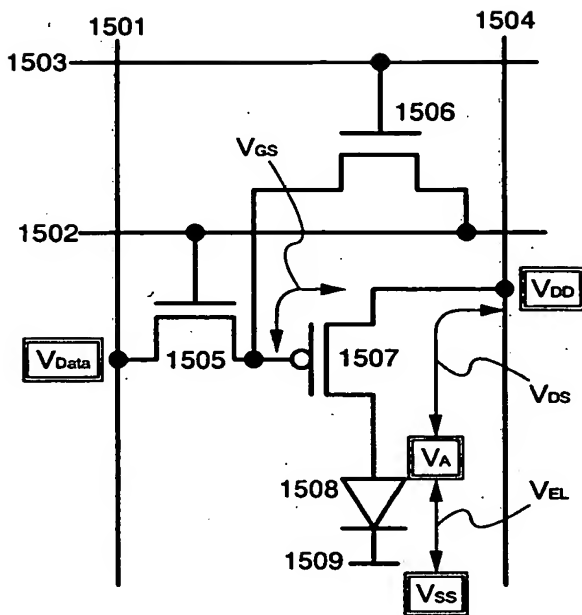


FIG.4B

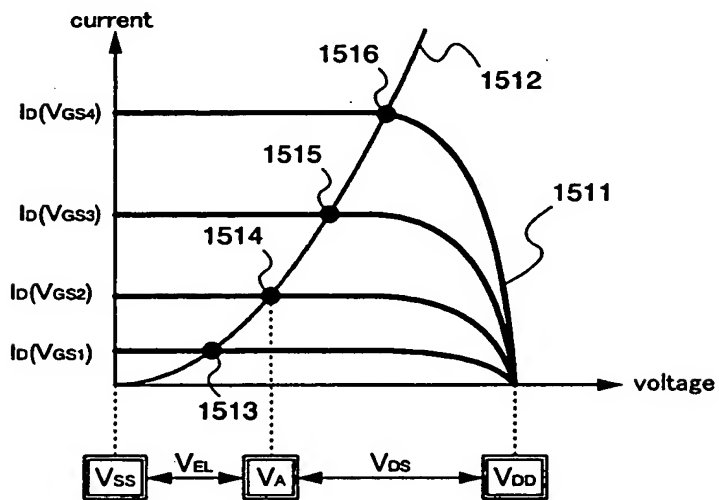


FIG.5

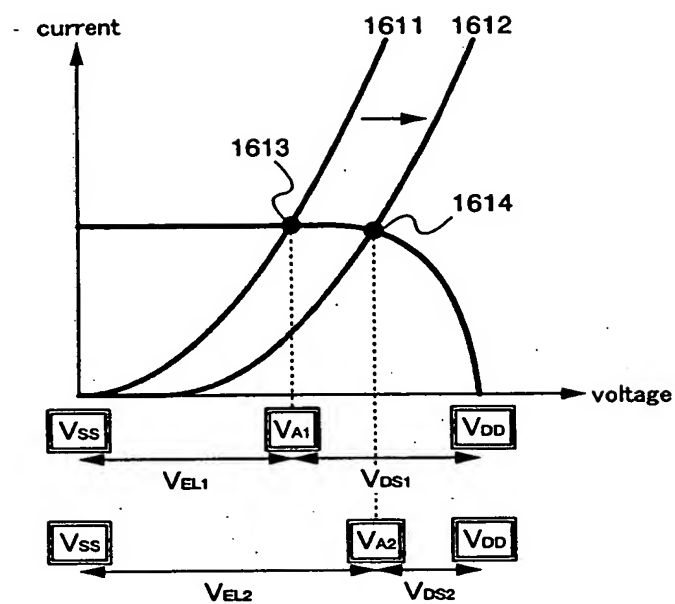


FIG. 6A

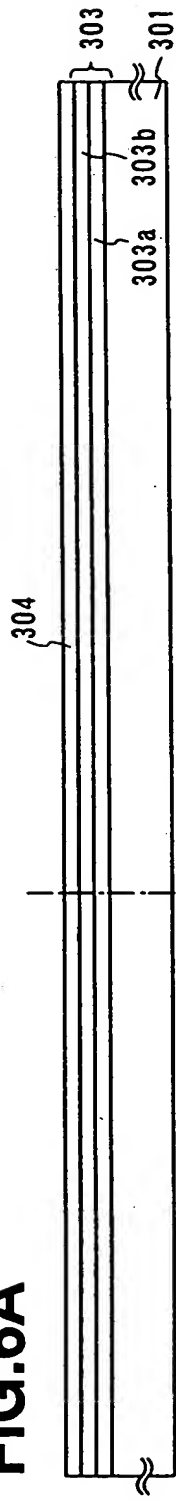


FIG. 6B

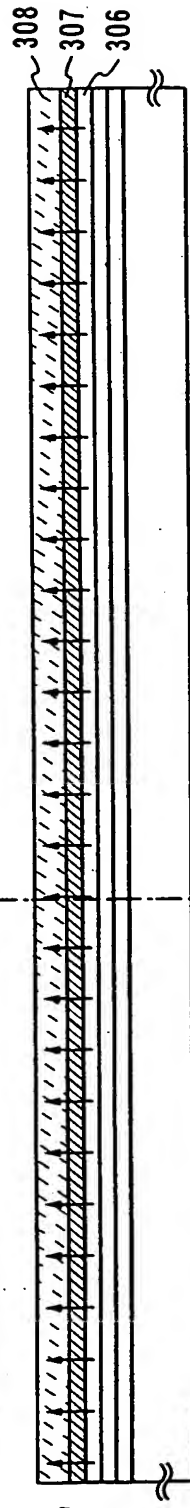


FIG. 6C

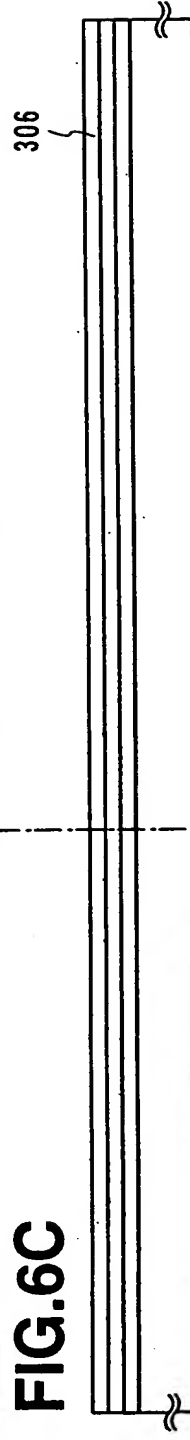


FIG. 6D

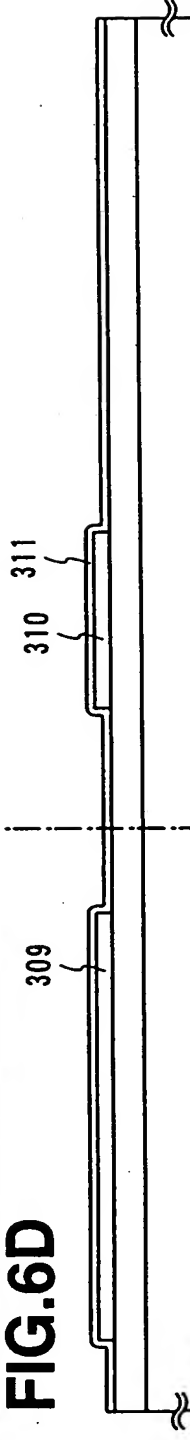


FIG. 6E

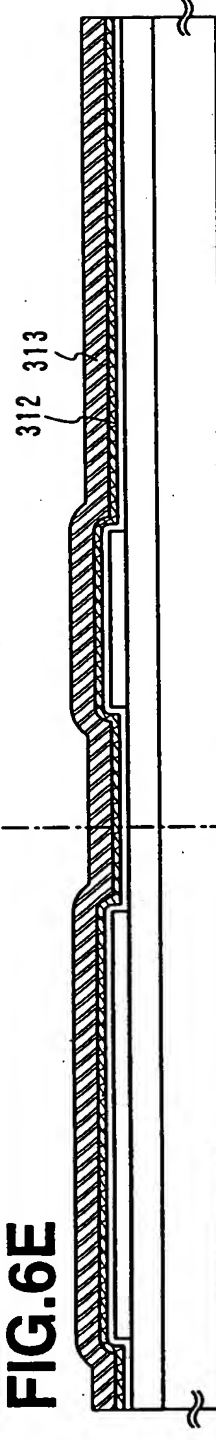


FIG. 7A

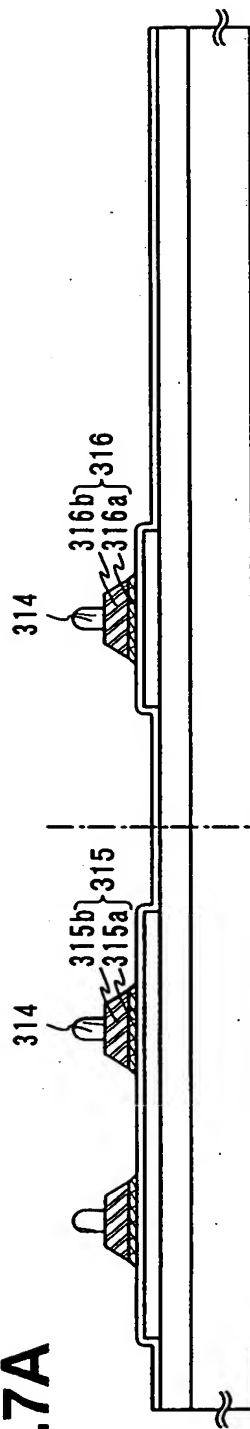


FIG. 7B

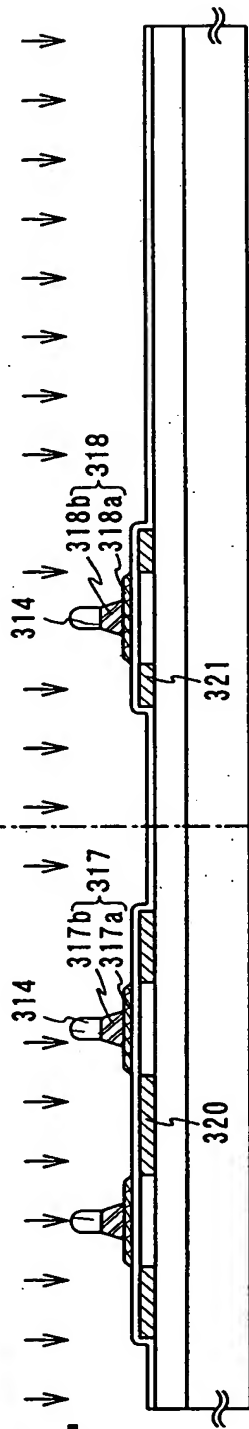


FIG. 7C

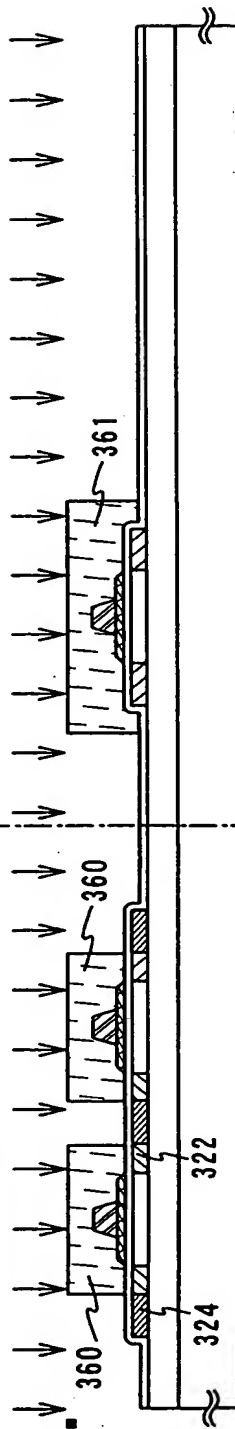


FIG. 7D

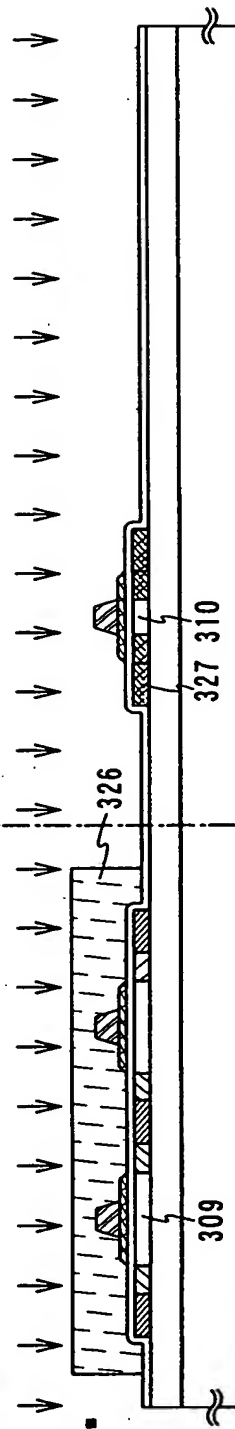
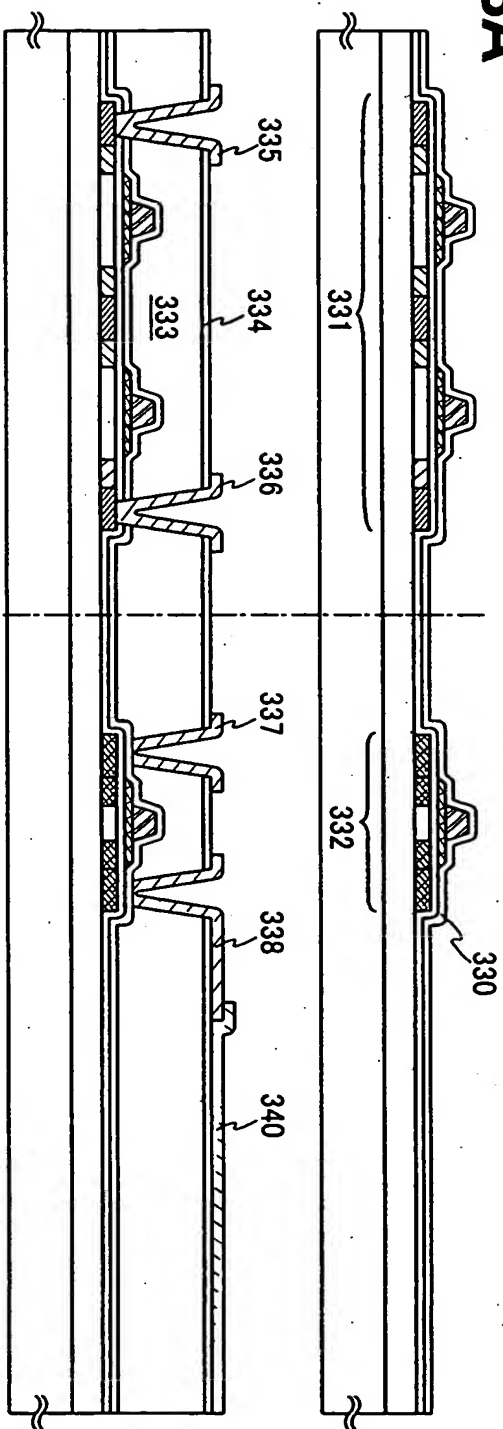
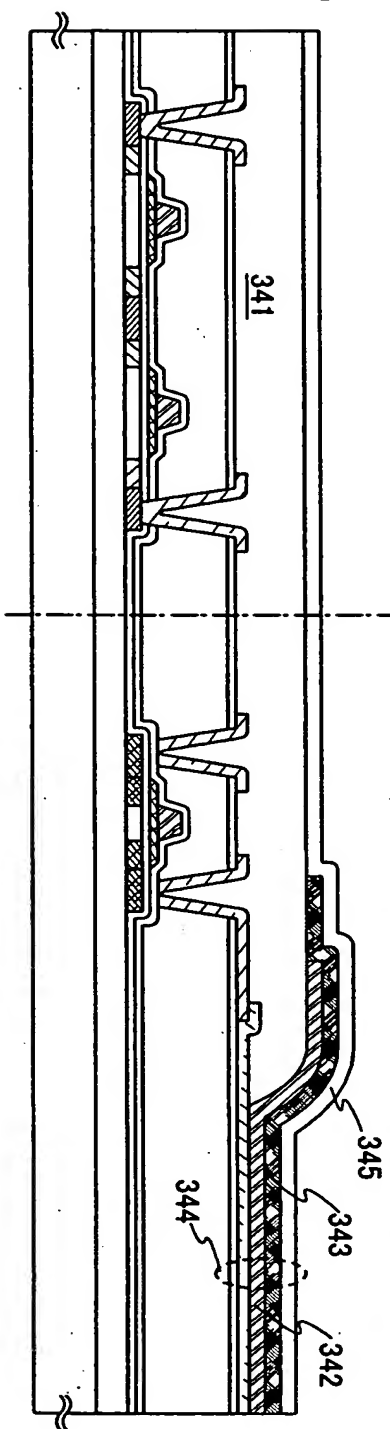


FIG.8A



**FIG.
8B**



**FIG.
8C**

FIG.9

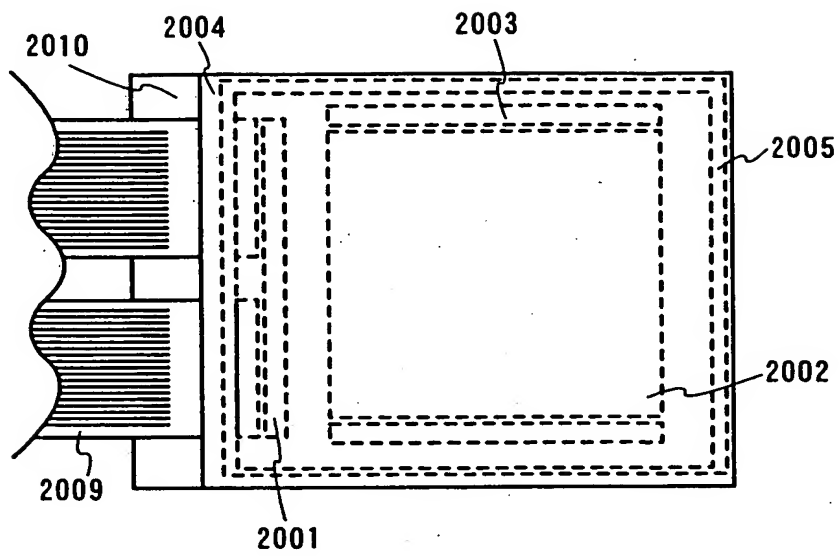


Fig.10A

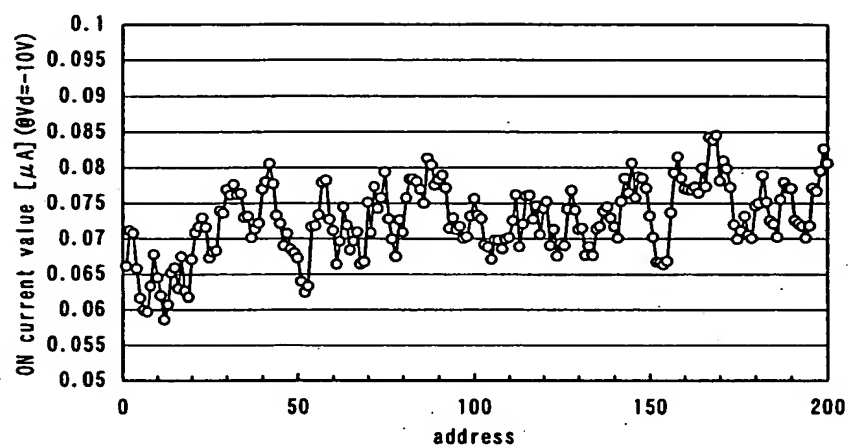


Fig.10B

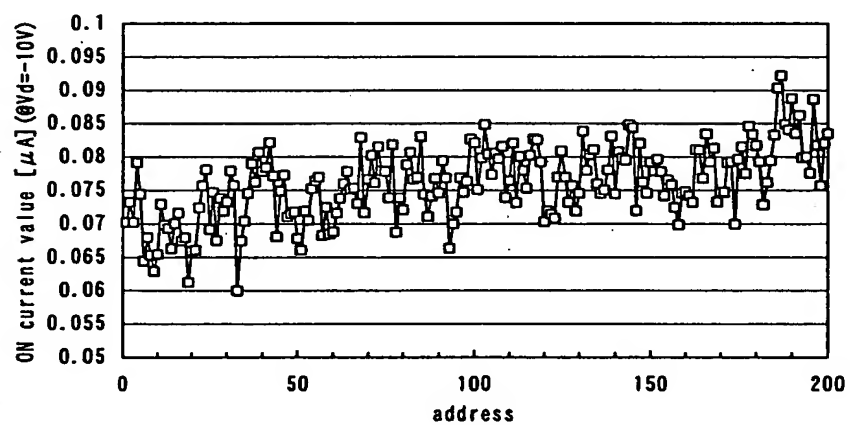


FIG. 11A

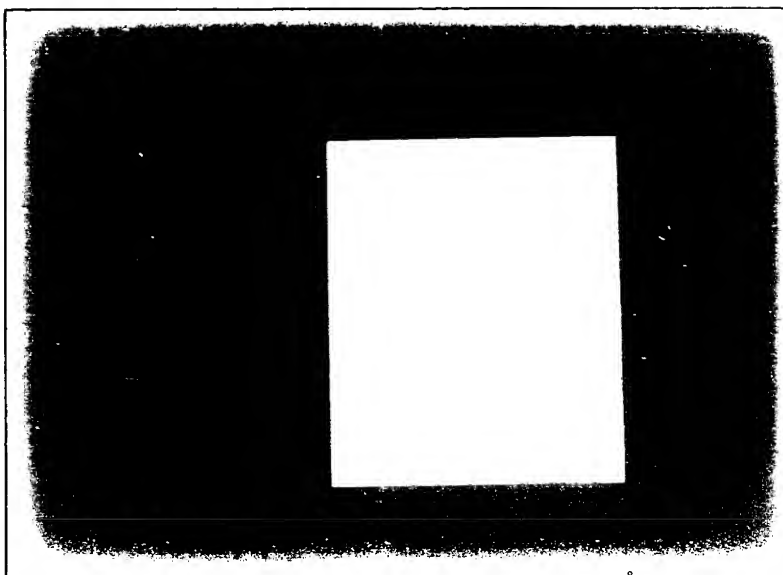
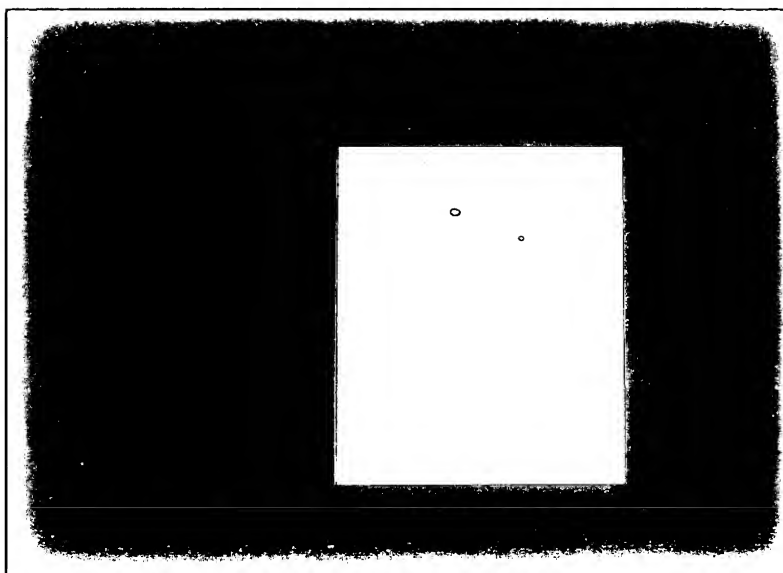


FIG. 11B



BEST AVAILABLE COP

FIG.12A

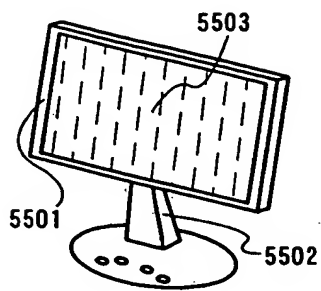


FIG.12B

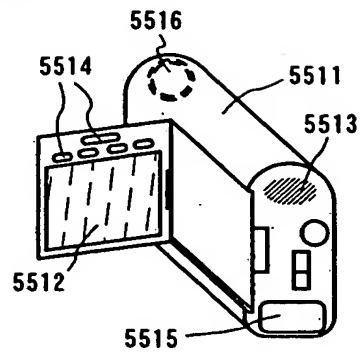


FIG.12C

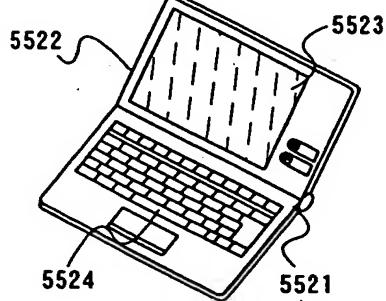


FIG.12D

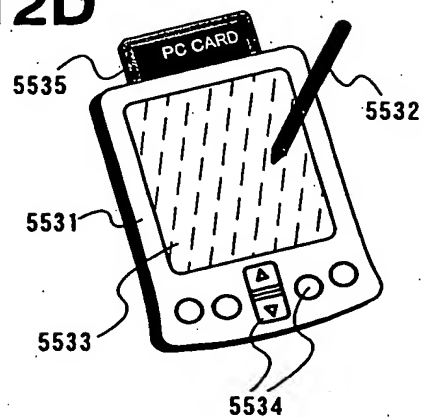


FIG.12E

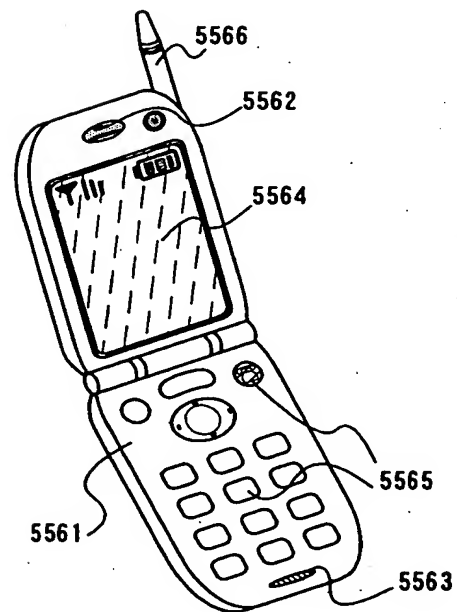
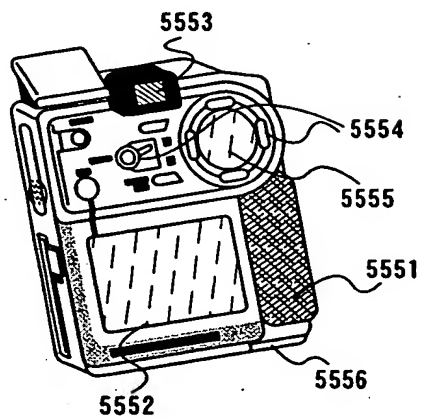


FIG.12F